TSX56x, TSX56xA

Micropower, wide bandwidth (900 kHz), 16 V CMOS operational amplifiers

Datasheet - production data

Features

- Low power consumption: 235 µA typ. at 5 V
- Supply voltage: 3 V to 16 V
- Gain bandwidth product: 900 kHz typ.
- Low offset voltage
	- "A" version: 600 µV max.
	- Standard version: 1 mV max.
- Low input bias current: 1 pA typ.
- High tolerance to ESD: 4 kV
- Wide temperature range: -40 to 125 °C
- Automotive qualification
- Tiny packages available: SOT23-5, DFN8 2 mm x 2 mm, MiniSO8, QFN16 3 mm x 3 mm, and TSSOP14

Benefits

Power savings in power-conscious applications

Easy interfacing with high impedance sensors

Related topics

- See TSX63x series for reduced power consumption (45 mA, 200 kHz)
- See TSX92x series for higher gain bandwidth products (10 MHz)

Applications

- Industrial and automotive signal conditioning
- Active filtering
- Medical instrumentation
- High impedance sensors

Description

The TSX56x, TSX56xA series of operational amplifiers benefit from STMicroelectronics® 16 V CMOS technology to offer state-of-the-art accuracy and performance in the smallest industrial packages. The TSX56x, TSX56xA have pinouts compatible with industrial standards and offer an outstanding speed/power consumption ratio, 900 kHz gain bandwidth product while consuming only 250 µA at 16 V. Such features make the TSX56x, TSX56xA ideal for sensor interfaces and industrial signal conditioning. The wide temperature range and high ESD tolerance ease use in harsh automotive applications.

Table 1: Device summary

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This is information on a product in full production. *www.st.com*

Contents

Figure 1: Pin connections for each package (top view) Single $\overline{\bullet}$ $\overline{5}$ $V_{\text{CC+}}$ $IN+$ V_{CC} \overline{c} $\overline{4}$ $IN -$ OUT $\overline{3}$ SOT23-5 (TSX56 1) Dual \bullet \bullet $VCC+$ OUT₁ $\overline{\mathbf{8}}$ $VCC+$ OUT $\overline{\mathbf{8}}$ $\overline{1}$ $\overline{1}$ $\overline{7}$ OUT₂ \overline{c} OUT₂ $IN1$ $\overline{7}$ $IN1 \overline{2}$ $IN1$ $\overline{6}$ $IN2 IN1+$ $\overline{\mathbf{3}}$ $\overline{\bf{6}}$ 3 $IN2 \overline{5}$ $VCC \overline{4}$ $IN2+$ vcc. $IN2+$ $\overline{4}$ $\overline{5}$ DFN8 2x2 (TSX562) MiniSO8 (TSX562) Quad $\overline{\bullet}$ OUT4 OUT1 OUT₁ $\overline{14}$ OUT4 $\frac{1}{2}$ $\overline{1}$ $\frac{1}{2}$ $N₄$ 14 13 $N1$ $\overline{2}$ 13 $IN1$ $\overline{12}$ $IN4+$ $IN1+$ $N4+$ $\overline{3}$ $12²$ $VCC+$ $\overline{11}$ VCC- $V_{\text{CC+}}$ $\overline{4}$ $\overline{11}$ $v_{\rm CC}$

1 Pinout information

 $\frac{1}{2}$ $\frac{1}{2}$ $\frac{1}{5}$ $\frac{2}{5}$ $\frac{1}{2}$ $\frac{1}{2}$

 $N2+$

 $N2$ $\sqrt{6}$

 $\overline{5}$

 $N3+$

OUT3

 $10₁$

 $\overline{9}$ $N3$

 $\frac{1}{10}$ N_C

 $\overline{9}$ $|IN3+$

 \mathbf{a} \overline{z} Ω

 NC $\overline{3}$

 $IN2+$

2 Absolute maximum ratings and operating conditions

Table 2: Absolute maximum ratings (AMR)

Notes:

(1)All voltage values, except the differential voltage are with respect to the network ground terminal.

(2) The differential voltage is the non-inverting input terminal with respect to the inverting input terminal.

 $^{(3)}V_{cc}$ - V_{in} must not exceed 18 V, Vin must not exceed 18 V

 (4) Input current must be limited by a resistor in series with the inputs.

(5)Rth are typical values.

 $^{(6)}$ Short-circuits can cause excessive heating and destructive dissipation.

(7)Human body model: 100 pF discharged through a 1.5 kΩ resistor between two pins of the device, done for all couples of pin combinations with other pins floating.

(8)Machine model: a 200 pF cap is charged to the specified voltage, then discharged directly between two pins of the device with no external series resistor (internal resistor < 5 Ω), done for all couples of pin combinations with other pins floating.

(9)Charged device model: all pins plus package are charged together to the specified voltage and then discharged directly to ground.

3 Electrical characteristics

Table 4: Electrical characteristics at VCC+ = 3.3 V with VCC- = 0 V, Vicm = VCC/2, Tamb = 25 ° C, and R^L = 10 kΩ connected to VCC/2 (unless otherwise specified)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
DC performance						
V_{i0}	Offset voltage	TSX56xA, $T = 25 °C$			600	μV
		TSX56xA, -40 °C < T < 125 °C			1800	
		TSX56x, $T = 25 °C$			$\mathbf{1}$	mV
		TSX56x, -40 °C < T < 125 °C			2.2	
$\Delta V_{io}/\Delta T$	Input offset voltage drift	-40 °C < T < 125 °C (1)		2	12	µV/°C
I_{ib}	Input bias current, $V_{\text{out}} = V_{\text{CC}}/2$	$T = 25 °C$		1	100(2)	рA
		$-40 °C < T < 125 °C$		1	200(2)	
lio	Input offset current, $V_{\text{out}} = V_{\text{CC}}/2$	$T = 25 °C$		1	100(2)	
		$-40 °C < T < 125 °C$		1	200(2)	
	Common mode rejection	$T = 25 °C$	63	80		dB
CMR1	ratio, $CMR = 20 log$ $(\Delta V_{ic}/\Delta V_{io})$, $V_{ic} = -0.1$ V to V_{CC} - 1.5 V, $V_{out} = V_{CC}/2$, $R_L > 1 M\Omega$	$-40 °C < T < 125 °C$	59			
	Common mode rejection	$T = 25 °C$	47	66		
CMR ₂	ratio, $CMR = 20 log$ $(\Delta V_{\rm ic}/\Delta V_{\rm io})$, $V_{\rm ic}$ = -0.1 V to V_{CC} + 0.1 V, V_{out} = $V_{CC}/2$, $R_L > 1 M\Omega$	$-40 °C < T < 125 °C$	45			
$A_{\rm Vd}$	Large signal voltage gain, $V_{\text{out}} = 0.5 V$ to (Vcc - 0.5 V), $R_L > 1 M\Omega$	$T = 25 °C$	85			
		$-40 °C < T < 125 °C$	83			
V _{OH}	High-level output voltage, $V_{OH} = V_{CC} - V_{out}$	$T = 25 °C$			70	mV
		$-40 °C < T < 125 °C$			100	
Vol	Low-level output voltage	$T = 25 °C$			70	
		$-40 °C < T < 125 °C$			100	
I_{out}	I_{sink} , $V_{\text{out}} = V_{\text{CC}}$	$T = 25 °C$	4.3	5.3		mA
		$-40 °C < T < 125 °C$	2.5			
	I_{source} , $V_{out} = 0$ V	$T = 25 °C$	3.3	4.3		
		$-40 °C < T < 125 °C$	2.5			
$_{\text{Lcc}}$	Supply current, per channel, $V_{\text{out}} = V_{\text{CC}}/2$, $R_L > 1 M\Omega$	$T = 25 °C$		220	300	μA
		$-40 °C < T < 125 °C$			350	
AC performance						
GBP	Gain bandwidth product	R_L = 10 k Ω , C_L = 100 pF	600	800		kHz
F_u	Unity gain frequency			690		
фm	Phase margin			55		Degrees
G_m	Gain margin			9		dB

TSX56x, TSX56xA Electrical characteristics

Notes:

(1)See *Section [5.3: "Input offset voltage drift over temperature"](#page-15-3)* (2)Guaranteed by design

 $\sqrt{2}$

TSX56x, TSX56xA Electrical characteristics

Notes:

(1)See *[Section 5.3: "Input offset voltage drift over temperature"](#page-15-3)*

⁽²⁾Typical value is based on the V_{io} drift observed after 1000h at 125 °C extrapolated to 25 °C using the Arrhenius law and assuming an activation energy of 0.7 eV. The operational amplifier is aged in follower mode configuration.

(3)Guaranteed by design

Table 6: Electrical characteristics at VCC+ = 16 V with VCC- = 0 V, Vicm = VCC/2, Tamb = 25 ° C, and R^L = 10 kΩ connected to VCC/2 (unless otherwise specified)

 $R_L > 1 M\Omega$

 $-40 \text{ °C} < T < 125 \text{ °C}$ 400

TSX56x, TSX56xA Electrical characteristics

Notes:

(1)See *[Section 5.3: "Input offset voltage drift over temperature"](#page-15-3)*

⁽²⁾Typical value is based on the V_{io} drift observed after 1000h at 125 °C extrapolated to 25 °C using the Arrhenius law and assuming an activation energy of 0.7 eV. The operational amplifier is aged in follower mode configuration.

 $^{(3)}$ Guaranteed by design

150 125

100

75

4 Electrical characteristic curves

 V_{icm}

 $V_{\rm CC}/2$

 15

 $10₁$

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TSX56x, TSX56xA Electrical characteristic curves

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Electrical characteristic curves **TSX56x, TSX56xA**

100 100 ⊞ $V_{icm} = 1.65 V$ V_{icm} $= 2.5$ 10 10 0.01 0.1 10 0.01 100 0.1 10 Frequency (kHz) Frequency (kHz)

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100

TSX56x, TSX56xA Electrical characteristic curves

5 Application information

5.1 Operating voltages

The amplifiers of the TSX56x and TSX56xA series can operate from 3 V to 16 V. Their parameters are fully specified at 3.3 V, 5 V, and 16 V power supplies. However, the parameters are very stable in the full V_{CC} range. Additionally, the main specifications are guaranteed in extended temperature ranges from -40 to 125 ° C.

5.2 Rail-to-rail input

The TSX56x and TSX56xA devices are built with two complementary PMOS and NMOS input differential pairs. The devices have a rail-to-rail input, and the input common mode range is extended from $(V_{CC}$ -) - 0.1 V to $(V_{CC}$ +) + 0.1 V.

However, the performance of these devices is clearly optimized for the PMOS differential pairs (which means from (V_{CC}) - 0.1 V to (V_{CC}) - 1.5 V).

Beyond (V_{CC} +) - 1.5 V, the operational amplifiers are still functional but with degraded performance, as can be observed in the electrical characteristics section of this datasheet (mainly Vio and GBP). These performances are suitable for a number of applications that need to be rail-to-rail.

The devices are designed to prevent phase reversal.

5.3 Input offset voltage drift over temperature

The maximum input voltage drift over the temperature variation is defined as the offset variation related to the offset value measured at 25 °C. The operational amplifier is one of the main circuits of the signal conditioning chain, and the amplifier input offset is a major contributor to the chain accuracy. The signal chain accuracy at 25 °C can be compensated during production at application level. The maximum input voltage drift over temperature enables the system designer to anticipate the effects of temperature variations.

The maximum input voltage drift over temperature is computed using *[Equation 1](#page-15-4)*.

Equation 1

$$
\frac{\Delta V_{io}}{\Delta T} = max \left| \frac{V_{io}(T) - V_{io}(25 \text{ °C})}{T - 25 \text{ °C}} \right|
$$

Where T = -40 $^{\circ}$ C and 125 $^{\circ}$ C.

The datasheet maximum value is guaranteed by measurements on a representative sample size ensuring a C_{pk} (process capability index) greater than 2.

5.4 Long term input offset voltage drift

To evaluate product reliability, two types of stress acceleration are used:

- Voltage acceleration, by changing the applied voltage
- Temperature acceleration, by changing the die temperature (below the maximum junction temperature allowed by the technology) with the ambient temperature.

The voltage acceleration has been defined based on JEDEC results, and is defined using *[Equation 2](#page-16-1)*.

Equation 2

$$
A_{FV} = e^{\beta \cdot (V_S - V_U)}
$$

Where:

A_{FV} is the voltage acceleration factor

β is the voltage acceleration constant in 1/V, constant technology parameter (β = 1)

V_s is the stress voltage used for the accelerated test

 V_U is the voltage used for the application

The temperature acceleration is driven by the Arrhenius model, and is defined in *[Equation 3](#page-16-2)*.

Equation 3

$$
A_{FT} = e^{\frac{E_a}{k} \cdot \left(\frac{1}{T_U} - \frac{1}{T_S}\right)}
$$

Where:

A_{FT} is the temperature acceleration factor

E^a is the activation energy of the technology based on the failure rate

k is the Boltzmann constant (8.6173 x 10 5 eV.K -1)

 T_U is the temperature of the die when V_U is used (K)

 Ts is the temperature of the die under temperature stress (K)

The final acceleration factor, A_F, is the multiplication of the voltage acceleration factor and the temperature acceleration factor (*[Equation 4](#page-16-3)*).

Equation 4

$$
A_F = A_{FT} \times A_{FV}
$$

AF is calculated using the temperature and voltage defined in the mission profile of the product. The A^F value can then be used in *[Equation 5](#page-16-4)* to calculate the number of months of use equivalent to 1000 hours of reliable stress duration.

Equation 5

Months = $A_F \times 1000$ h \times 12 months / (24 h \times 365.25 days)

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To evaluate the op amp reliability, a follower stress condition is used where V_{CC} is defined as a function of the maximum operating voltage and the absolute maximum rating (as recommended by JEDEC rules).

The V_{io} drift (in μ V) of the product after 1000 h of stress is tracked with parameters at different measurement conditions (see *[Equation 6](#page-17-2)*).

Equation 6

 V_{CC} = max V_{op} with V_{icm} = V_{CC} / 2

The long term drift parameter (ΔV_{io}) , estimating the reliability performance of the product, is obtained using the ratio of the Vio (input offset voltage value) drift over the square root of the calculated number of months (*[Equation 7](#page-17-3)*).

Equation 7

$$
\Delta V_{io} = \frac{V_{io}drift}{\sqrt{(month s)}}
$$

Where V_{io} drift is the measured drift value in the specified test conditions after 1000 h stress duration.

5.5 PCB layouts

For correct operation, it is advised to add 10 nF decoupling capacitors as close as possible to the power supply pins.

5.6 Macromodel

Accurate macromodels of the TSX56x, TSX56xA devices are available on the STMicroelectronics' website at: *www.st.com*. These models are a trade-off between accuracy and complexity (that is, time simulation) of the TSX56x and TSX56xA operational amplifiers. They emulate the nominal performance of a typical device within the specified operating conditions mentioned in the datasheet. They also help to validate a design approach and to select the right operational amplifier, *but they do not replace on-board measurements*.

6 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: *www.st.com*. ECOPACK[®] is an ST trademark.

6.1 SOT23-5 package information

Table 7: SOT23-5 mechanical data

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6.2 DFN8 2x2 package information

Table 8: DFN8 2x2 mechanical data

6.3 MiniSO8 package information

Table 9: MiniSO8 mechanical data

6.4 QFN16 3x3 package information

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Table 10: QFN16 3x3 mechanical data

6.5 TSSOP14 package information

Table 11: TSSOP14 mechanical data

7 Ordering information

Notes:

 (1) Qualified and characterized according to AEC Q100 and Q003 or equivalent, advanced screening according to AEC Q001 & Q 002 or equivalent

8 Revision history

Table 13: Document revision history

